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 Member of the Texas Instruments Widebus™ Family UBT™ (Universal Bus Transceiver) Combines D-Type Latches and D-Type Flip-Flops for Operation in Transparent, Latched, Clocked, or Clock-Enabled Mode EPIC™ (Enhanced-Performance Implanted CMOS) Submicron Process DGG OR DL PACKAGE (TOP VIEW) DGG OR DL PACKAGE (TOP VIEW) DGG OR DL PACKAGE (TOP VIEW) DEAB 1 56 CLKEN/ 2 55 CLKAB A1 3 54 B1 GND 4 53 GND A2 5 52 B2 	₩
Combines D-Type Latches and D-Type OEAB ↓ 1 56 ↓ CLKEN/ Flip-Flops for Operation in Transparent, LEAB ↓ 2 55 ↓ CLKAB Latched, Clocked, or Clock-Enabled Mode A1 ↓ 3 54 ↓ B1 <i>EPIC</i> ™ (Enhanced-Performance Implanted A2 ↓ 55 ↓ B2	٩B
Bus-Hold Data Inputs Eliminate the Need for External Pullup Resistors on All I/O Pins A3 [6 51] B3 V _{CC} [7 50] V _{CC} A4 [8 49] B4	
 Package Options Include Plastic 300-mil A5 [9 48] B5 Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages GND [11 46] GND A7 [12 45] B7 	
description A8 13 44 B8 This 18-bit universal bus transceiver is designed A9 14 43 B9 for 2.7-V to 3.6-V V _{CC} operation. A10 15 42 B10 The SN74ALVC162601 combines D-type latches A12 17 40 B12	
and D-type flip-flops to allow data flow inGND [18 39] GNDtransparent, latched, and clocked modes.A13 [19 38] B13	
Data flow in each direction is controlled byA142037B14output-enable (OEAB and OEBA), latch-enableA152136B15(LEAB and LEBA), and clock (CLKAB andV _{CC} 2235V _{CC} CLKBA) inputs. The clock can be controlled by theA162334B16clock-enable (CLKENAB and CLKENBA) inputs.A172433B17For A-to-B data flow, the device operates in theGND2532GND	

PRODUCT PREVIEW

Data flow for B to A is similar to that of A to B but uses OEBA, LEBA, CLKBA, and CLKENBA.

The B-port outputs, include $25 \cdot \Omega$ series resistors to reduce overshoot and undershoot.

The SN74ALVC162601 is available in TI's shrink small-outline (DL) and thin shrink small-outline (DGG) packages, which provide twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The SN74ALVC162601 is characterized for operation from -40°C to 85°C.

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transparent mode when LEAB is high. When

LEAB is low, the A data is latched if CLKAB is held

at a high or low logic level. If LEAB is low, the A-bus

data is stored in the latch/flip-flop on the high-to-low transition of CLKAB. Output enable OEAB is active low. When OEAB is low, the outputs are active. When OEAB is high, the

outputs are in the high-impedance state.



31 B18

29

30 CLKBA

CLKENBA

A18 26

OEBA

LEBA

27

28

SN74ALVC162601 **18-BIT UNIVERSAL BUS TRANSCEIVER** WITH 3-STATE OUTPUTS SCAS376 - MARCH 1994

FUNCTION TABLET						
	INPUTS			OUTPUT		
CLKENAB	OEAB	LEAB	CLKAB	Α	В	
Х	Н	Х	Х	Х	Z	
Х	L	Н	Х	L	L	
Х	L	Н	Х	Н	н	
н	L	L	Х	Х	в ₀ ‡ в ₀ ‡	
н	L	L	Х	Х	в ₀ ‡	
L	L	L	\uparrow	L	L	
L	L	L	\uparrow	Н	н	
L	L	L	L	Х	в ₀ ‡	
L	L	L	Н	Х	в ₀ ‡ в ₀ §	

.

[†]A-to-B data flow is shown: B-to-A flow is similar but uses OEBA, LEBA, CLKBA, and CLKENBA.

[‡] Output level before the indicated steady-state input conditions were established.

 $\$ Output level before the indicated steady-state input conditions were established, provided that CLKAB was low before LEAB went low.



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logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC} Input voltage range, V_I (except I/O ports) (see Note 1) Input voltage range, V_I (I/O ports) (see Notes 1 and 2)	$\begin{array}{c} -0.5 \ V \ to \ 4.6 \ V \\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$
Storage temperature range	1.4 W

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

- 2. This value is limited to 4.6 V maximum.
- 3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the Package Thermal Considerations application note.

recommended operating conditions

			MIN	MAX	UNIT	
VCC	Supply voltage		2.7	3.6	V	
VIH	High-level input voltage	$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2		V	
VIL	Low-level input voltage	$V_{CC} = 2.7 V \text{ to } 3.6 V$		0.8	V	
VI	Input voltage		0	VCC	V	
Vo	Output voltage		0	VCC	V	
ЮН	High-level output current	$V_{CC} = 2.7 V$			mA	
		$V_{CC} = 3 V$				
IOL	Low-level output current	$V_{CC} = 2.7 V$			mA	
		$V_{CC} = 3 V$				
$\Delta t / \Delta v$	Input transition rise or fall rate		0	10	ns/V	
TA	Operating free-air temperature		-40	85	°C	



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PA	RAMETER	TEST CONDITIONS	Vcc†	MIN	MAX	UNIT	
		I _{OH} = - 100 μA	MIN to MAX	V _{CC} -0.2	2		
V _{OH}		$I_{OH} = -4 \text{ mA}$	2.7 V	2.4		v	
		$I_{OH} = -6 \text{ mA}$	2.1/	2.4		v	
		I _{OH} = TBD	3 V	2			
		I _{OL} =100 μA	MIN to MAX		0.2		
VOL		I _{OL} = 4 mA	2.7 V		0.4	v	
0L	I _{OL} = 6 mA	2.14		0.4	V		
		I _{OH} = TBD	3 V			0.8	
Ц		V _I = V _{CC} or GND	3.6 V		±5	μA	
		V _I = 0.8 V	2.14	75			
l(hold)		V ₁ = 2 V	3 V	-75		μA	
loz‡		$V_{O} = V_{CC} \text{ or } GND$	3.6 V		±10	μA	
ICC		$V_{I} = V_{CC} \text{ or GND}, \qquad I_{O} = 0$	3.6 V		40	μA	
∆ICC		V_{CC} = 3 V to 3.6 V, One input at V_{CC} – 0.6 V, Other inputs at V_{CC} or GND			750	μA	
Ci	Control inputs	V _I = V _{CC} or GND	3.3 V			pF	
Cio	A or B ports	$V_{O} = V_{CC}$ or GND	3.3 V			pF	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

[†] For conditions shown as MIN or MAX, use the appropriate values under recommended operating conditions.

 \ddagger For I/O ports, the parameter I_{OZ} includes the input leakage current.



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